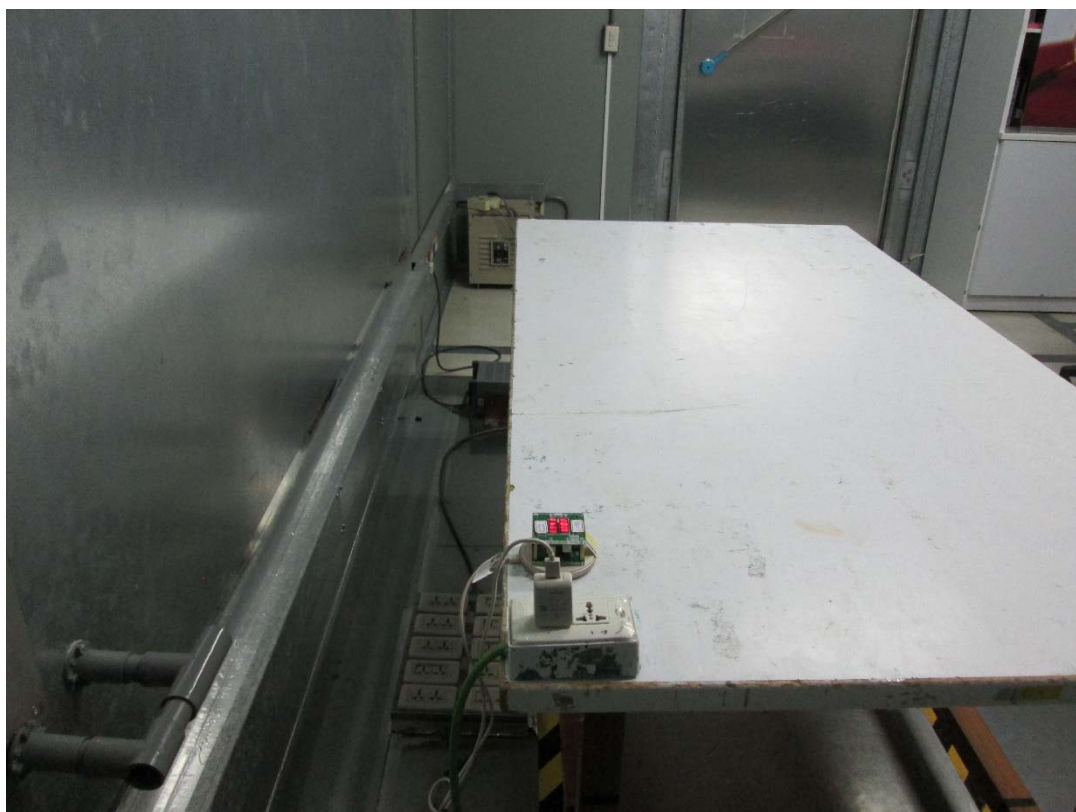


PHOTOGRAPHS OF THE TEST CONFIGURATION

Conducted Emission Test
Test Mode A (EUT sample No.:009-007)



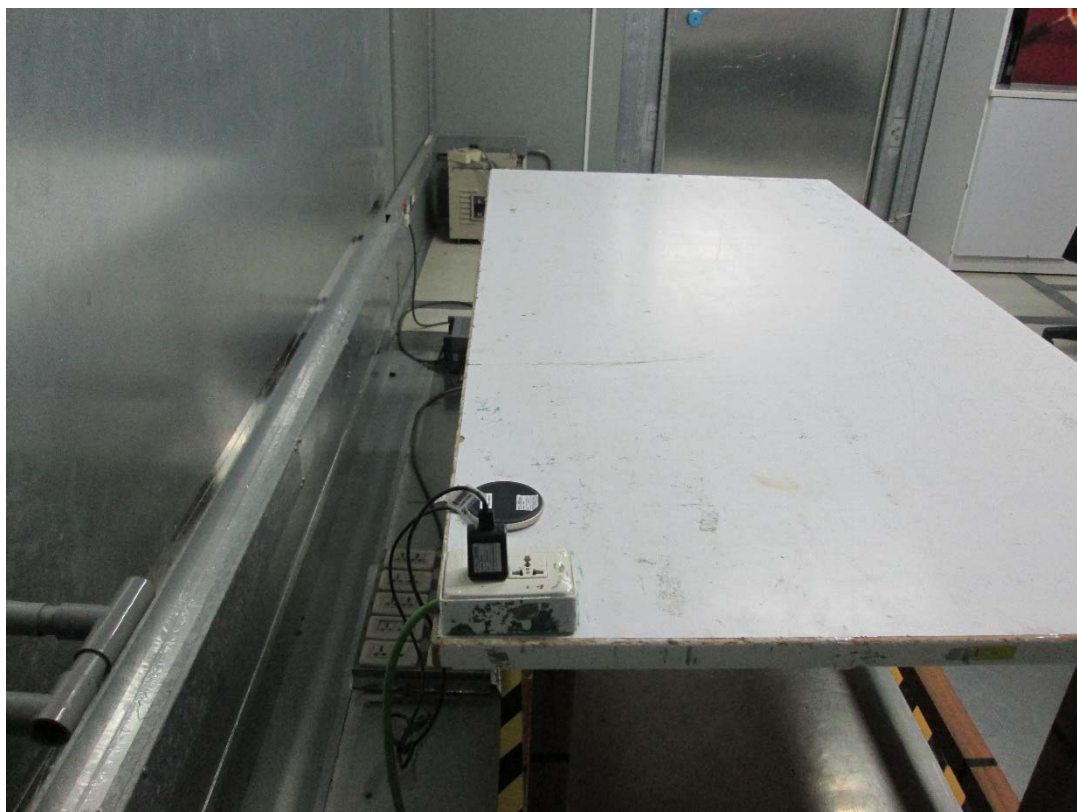
Test Mode B (EUT sample No.:009-007)



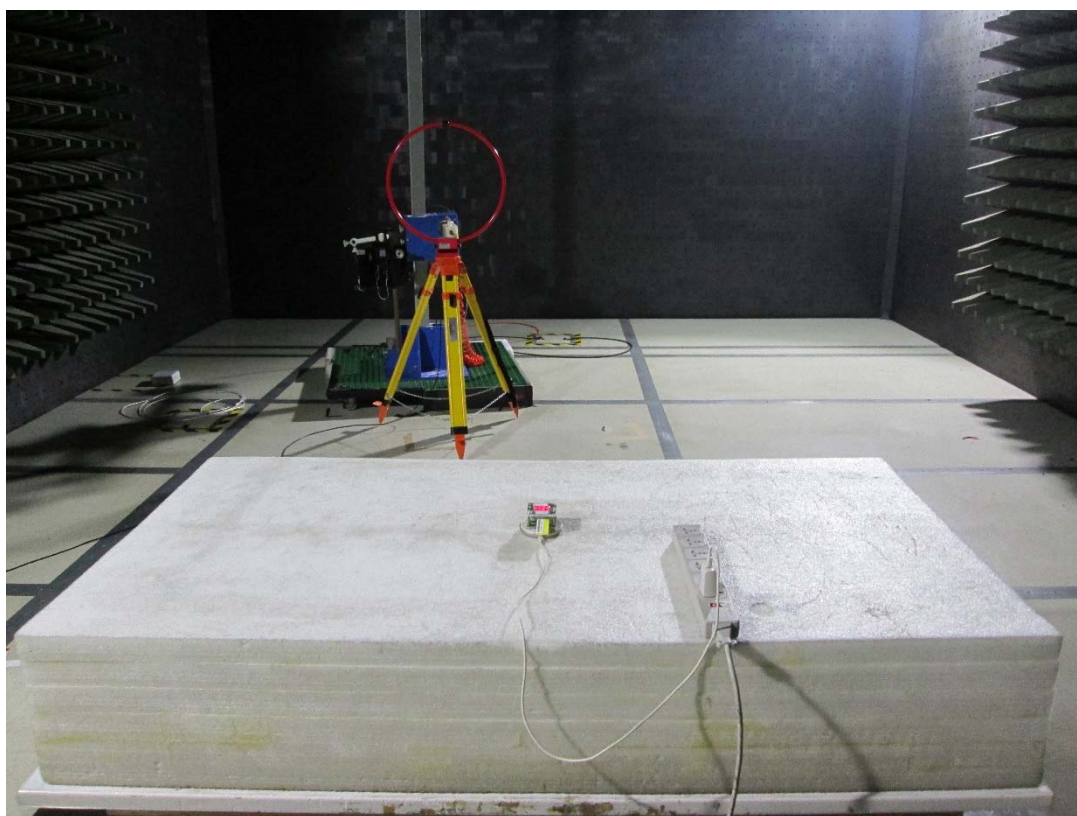
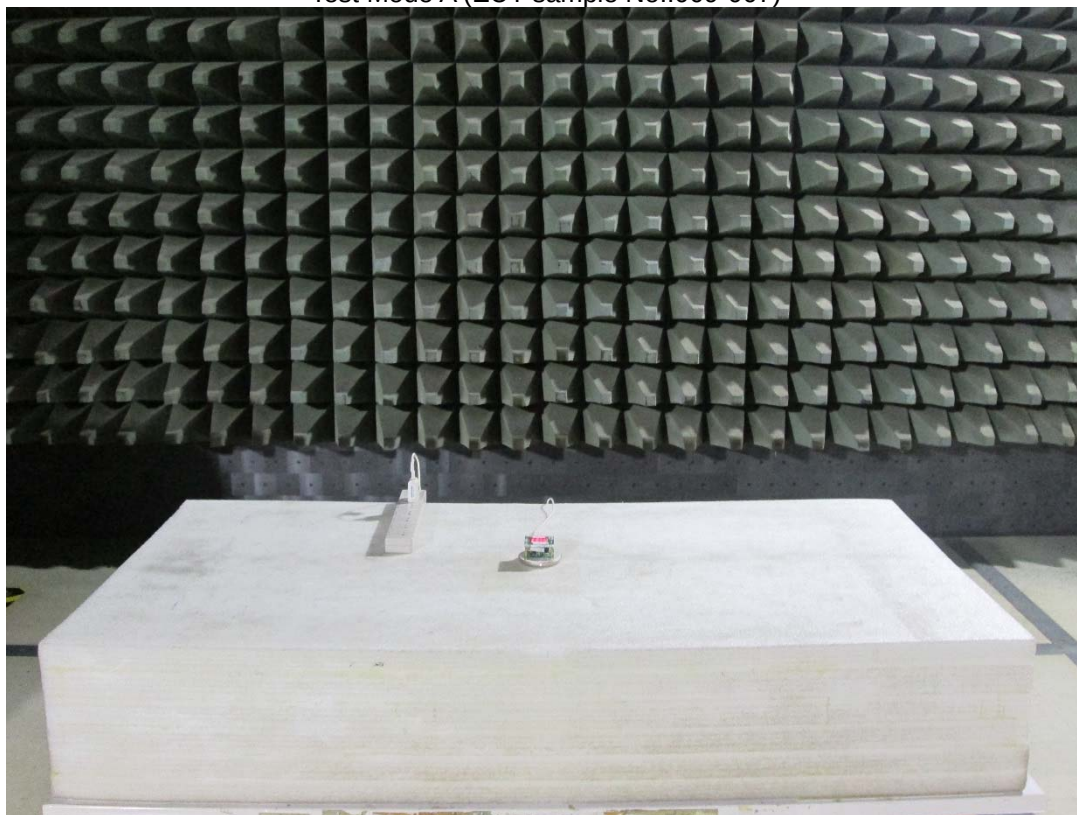
Test Mode C (EUT sample No.:006-001)



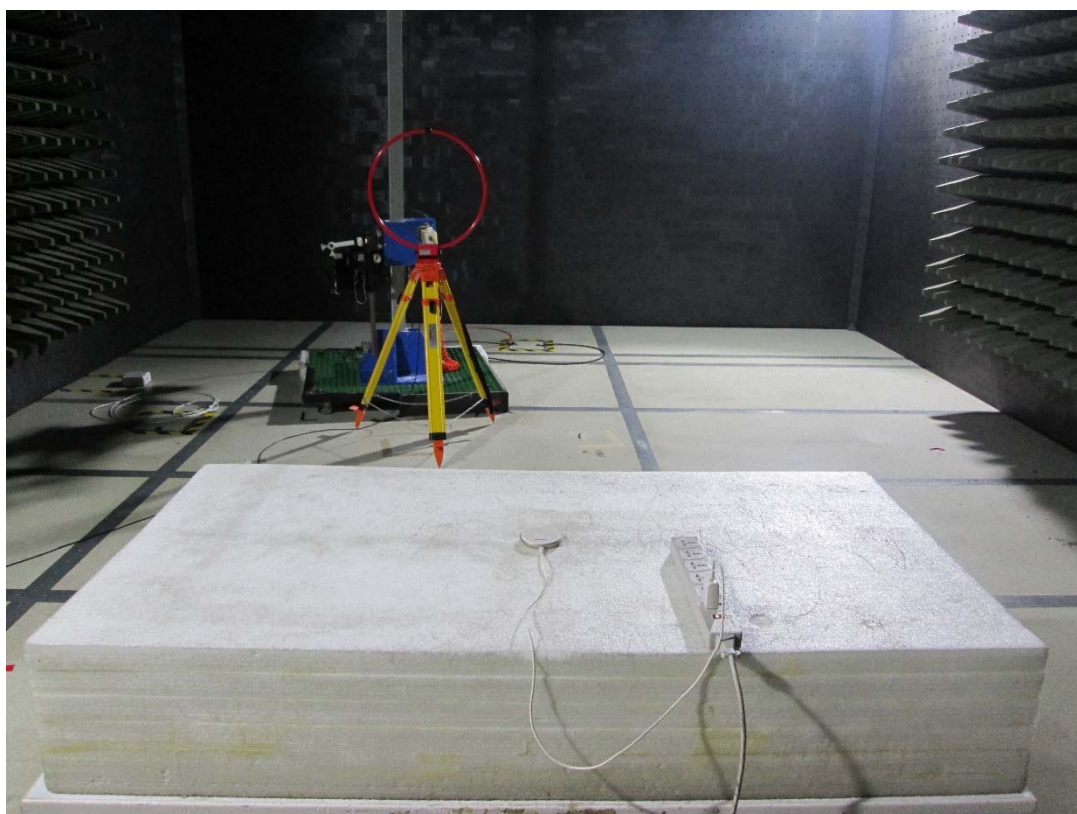
Test Mode D (EUT sample No.:006-001)



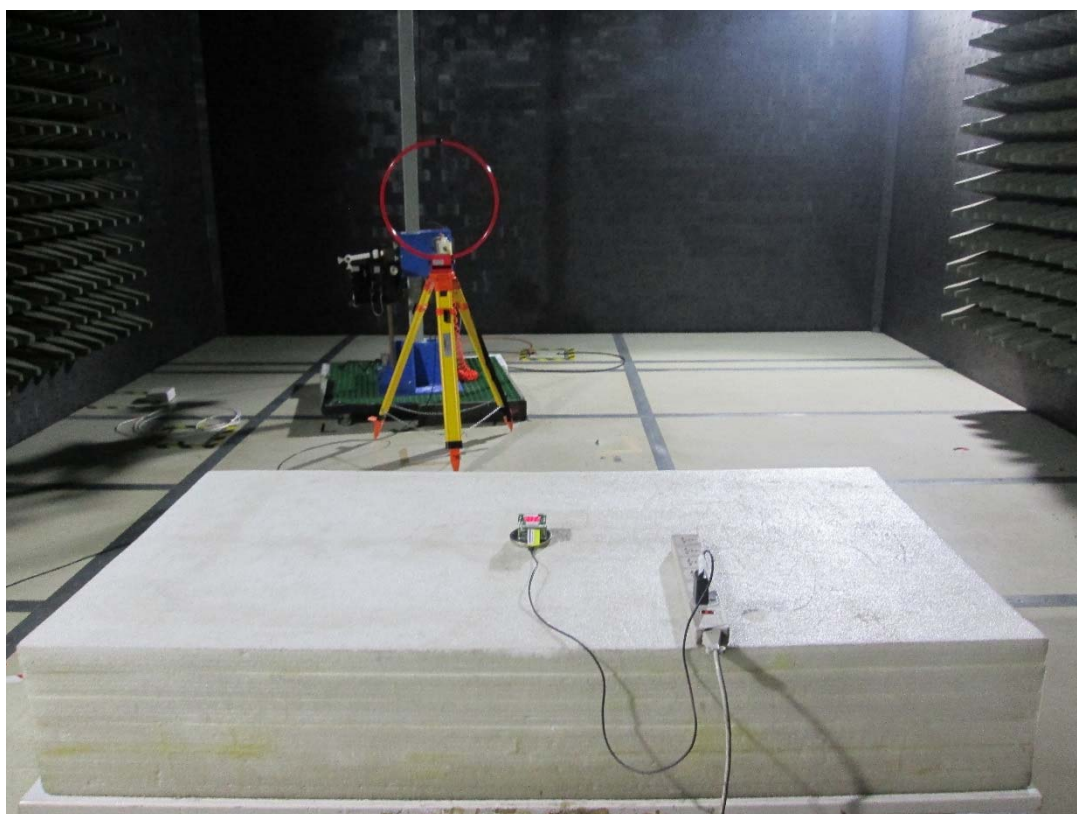
Radiated Emission Test (9kHz ~ 30MHz)
Test Mode A (EUT sample No.:009-007)



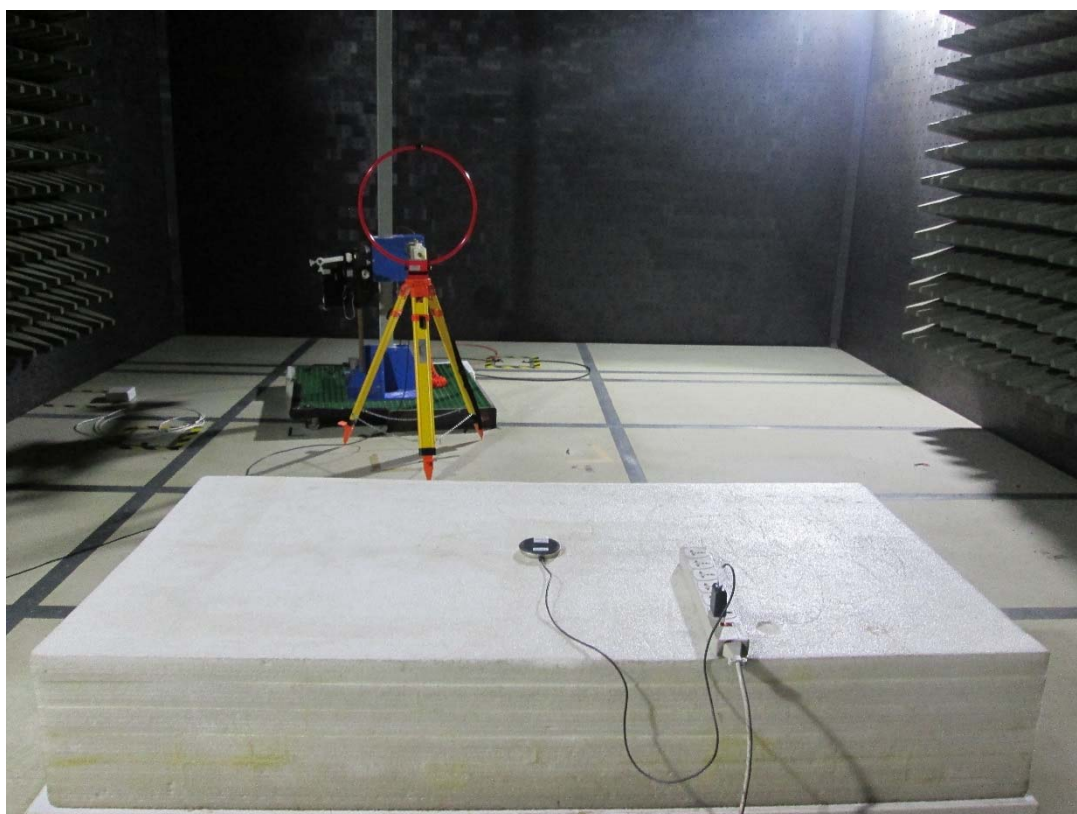
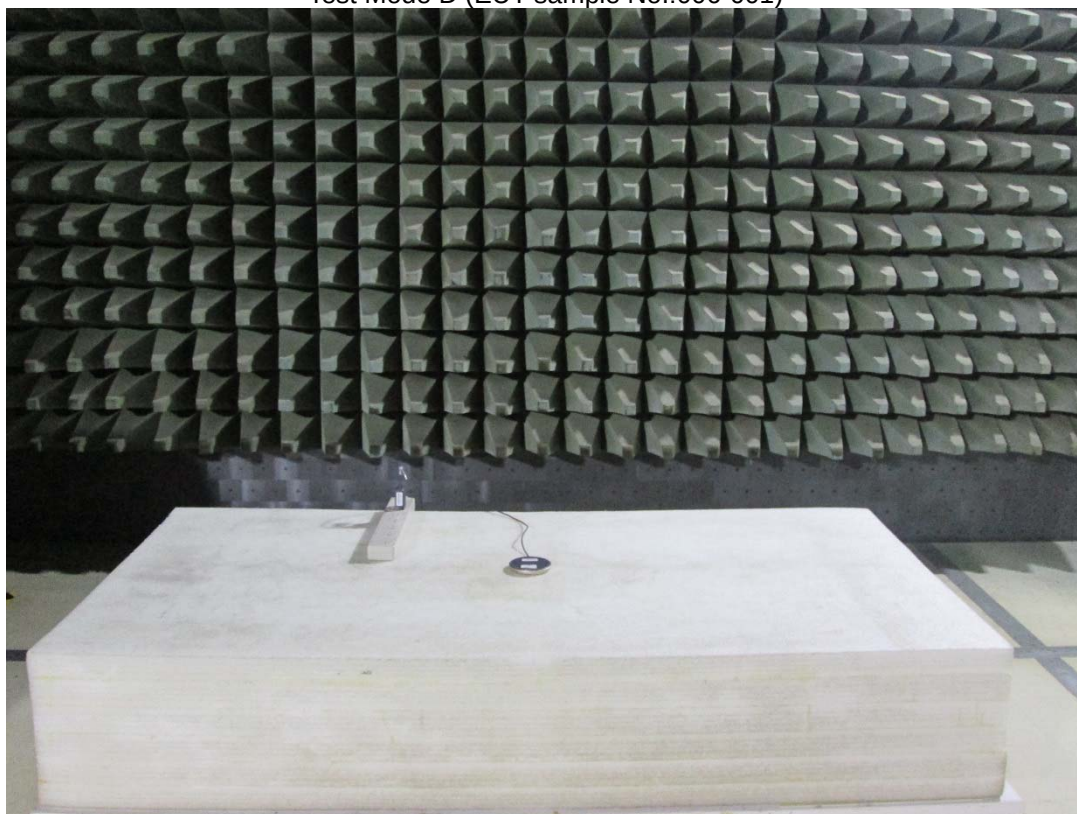
Test Mode B (EUT sample No.:009-007)



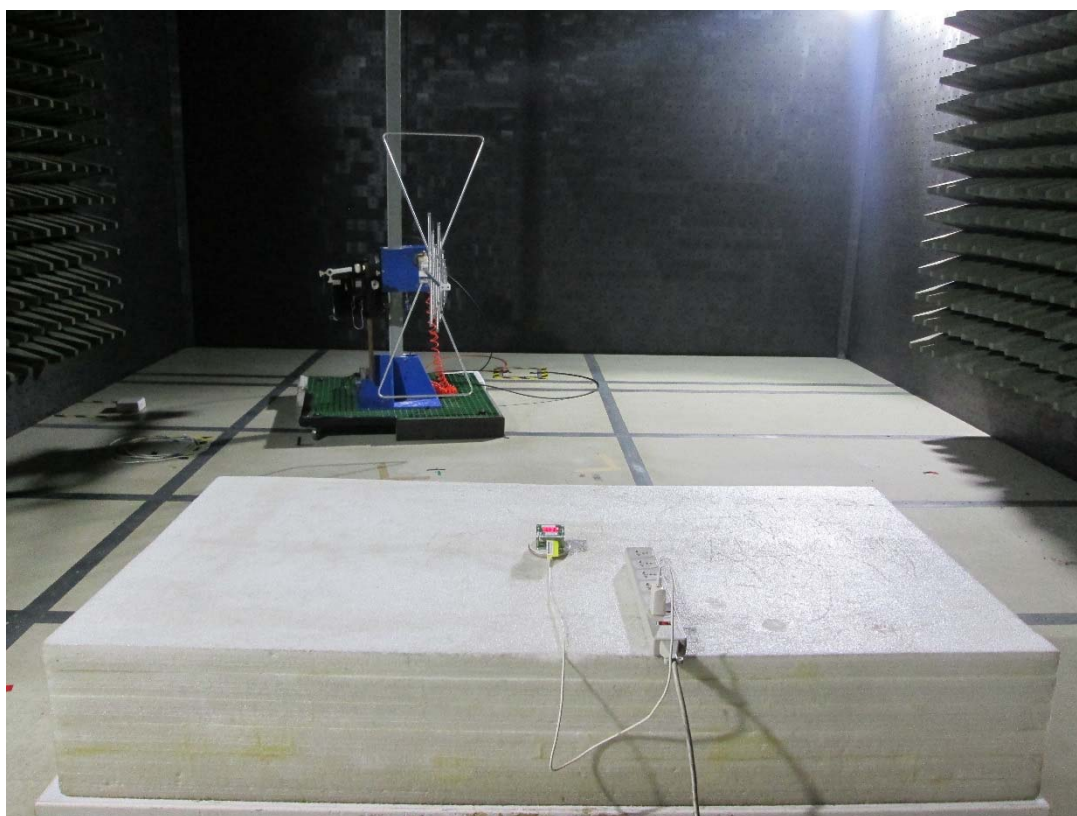
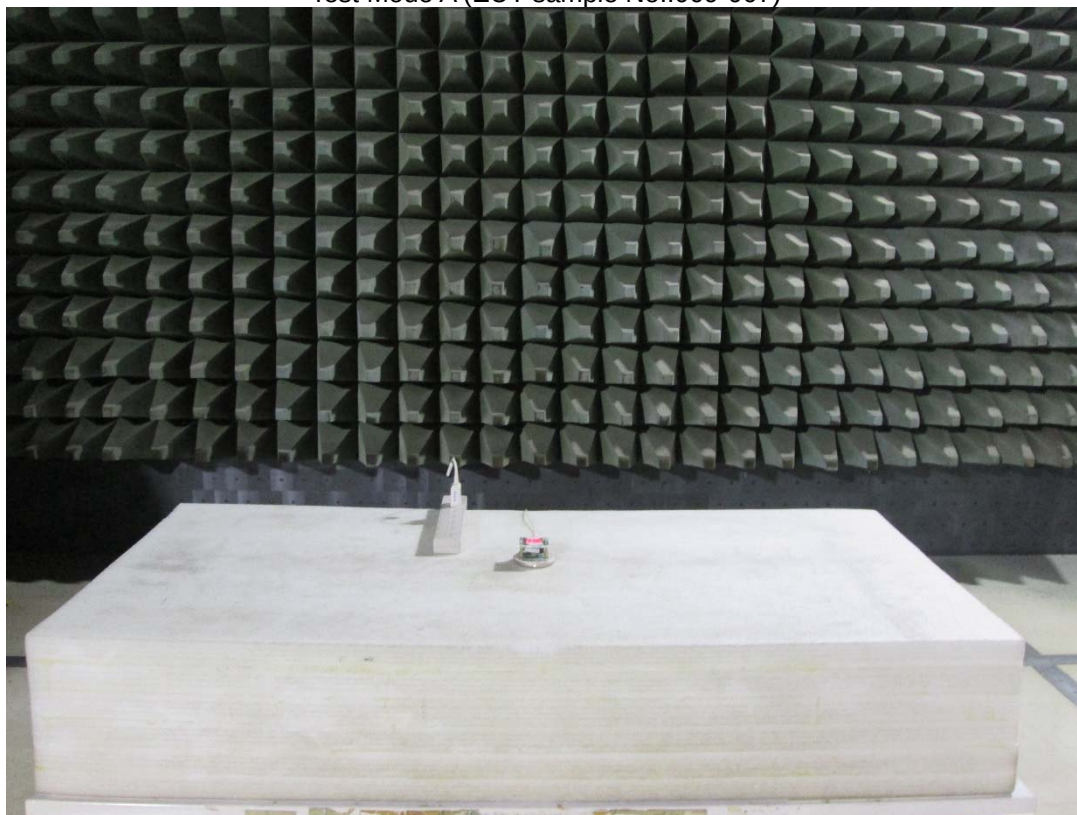
Test Mode C (EUT sample No.:006-001)



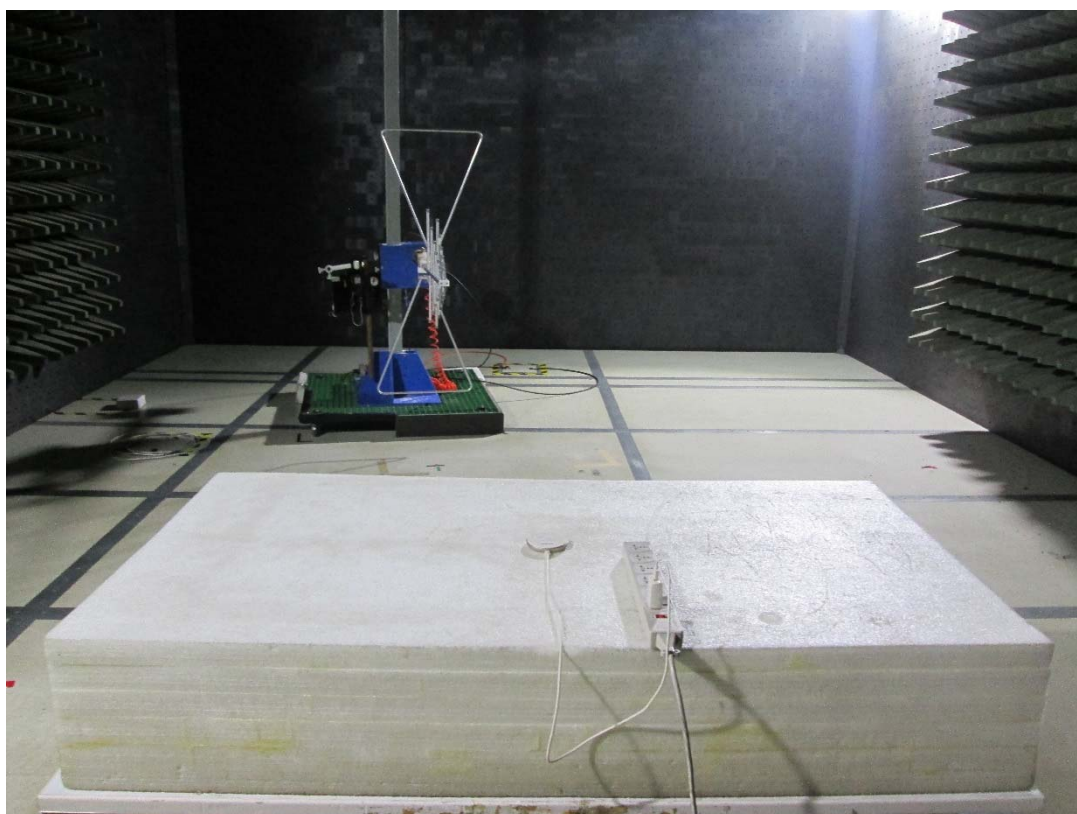
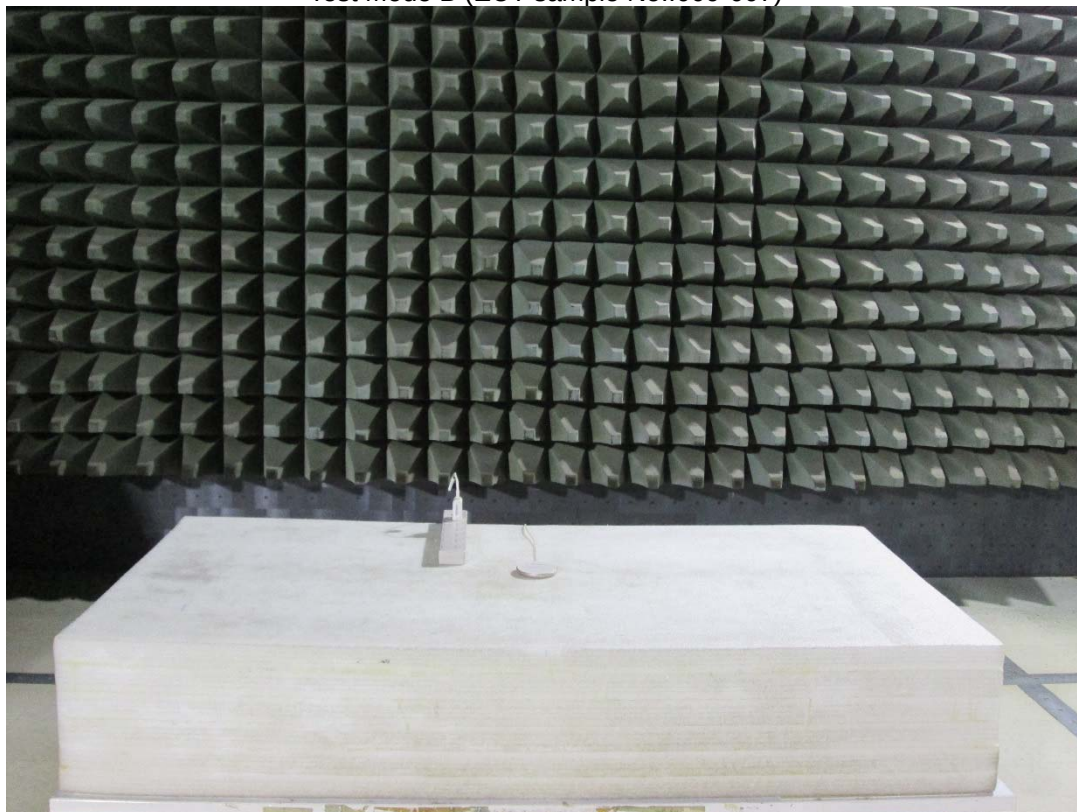
Test Mode D (EUT sample No.:006-001)



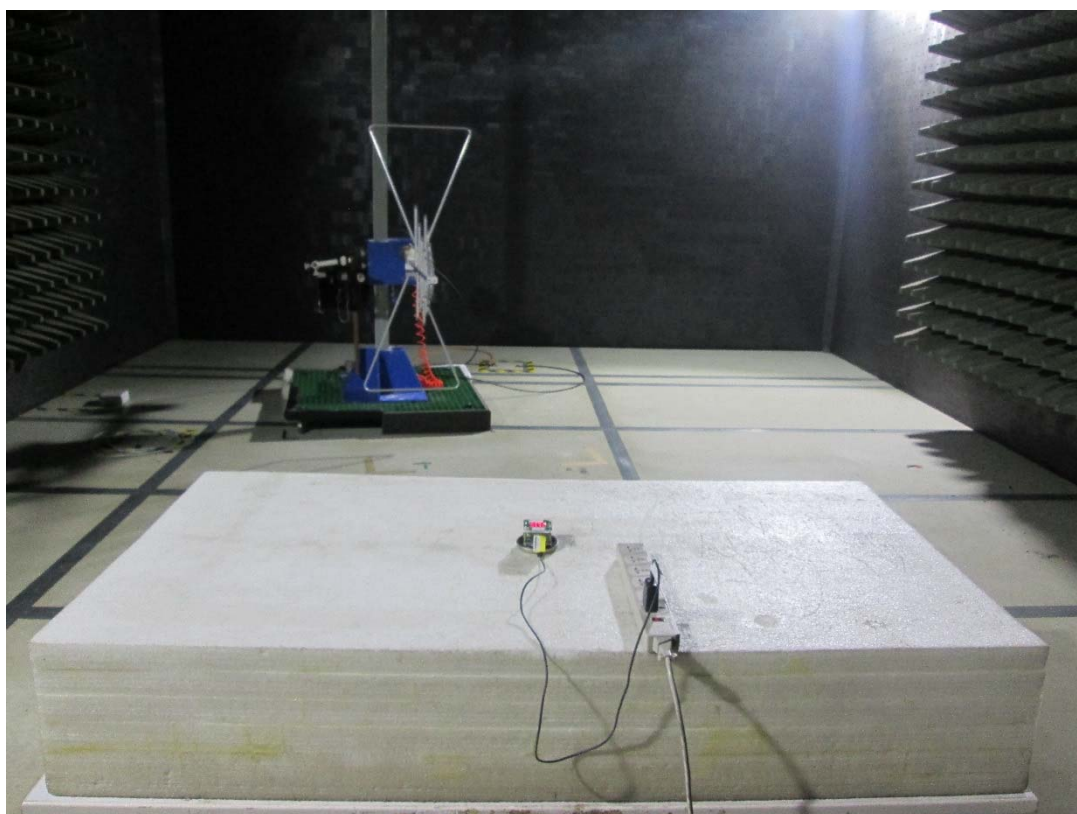
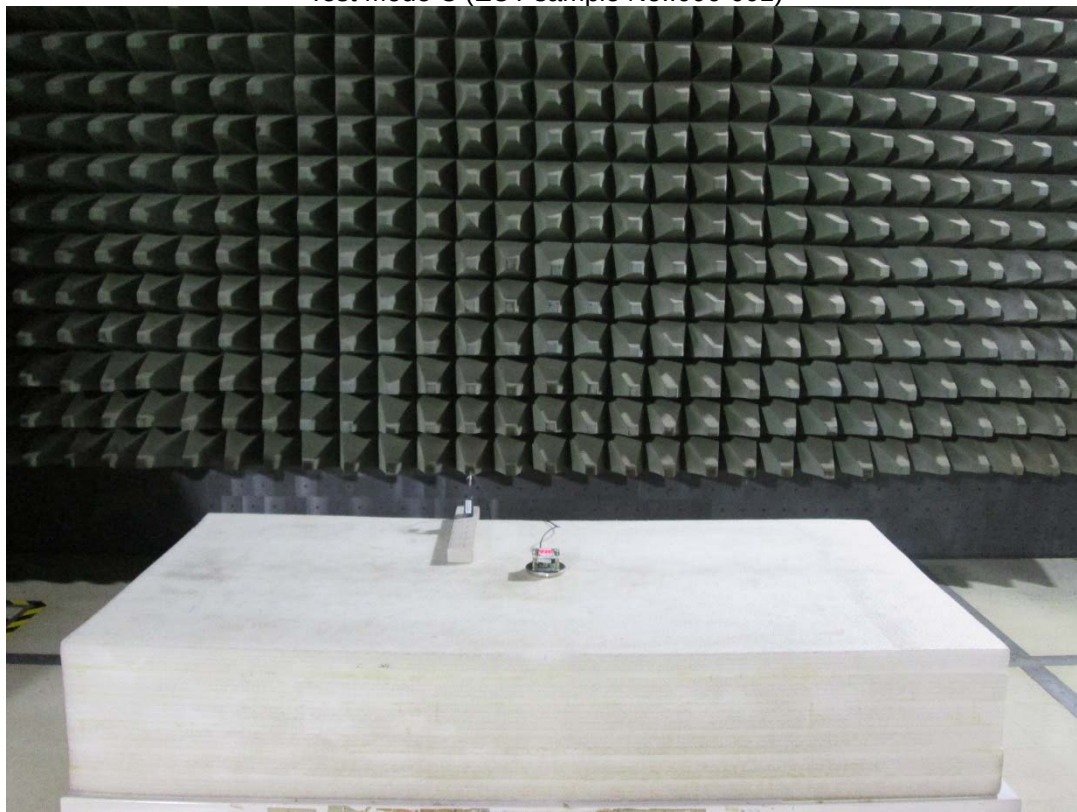
Radiated Emission Test (30MHz ~ 1GHz)
Test Mode A (EUT sample No.:009-007)



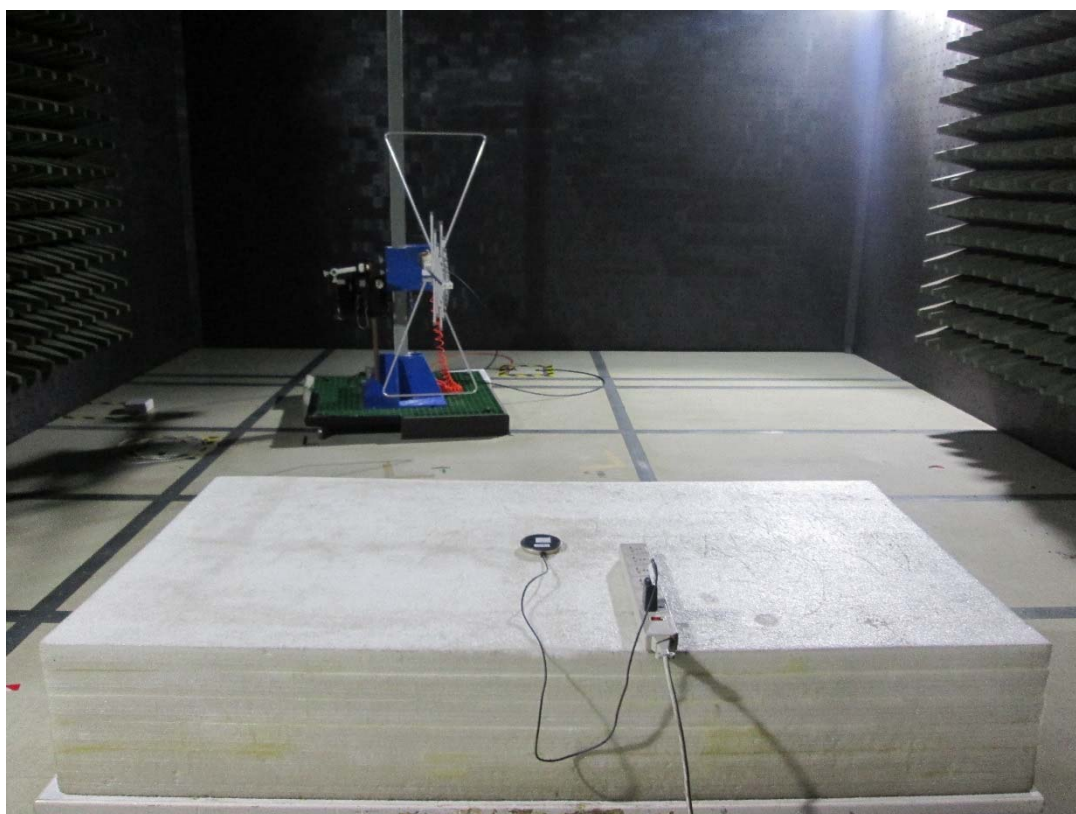
Test Mode B (EUT sample No.:009-007)



Test Mode C (EUT sample No.:006-001)

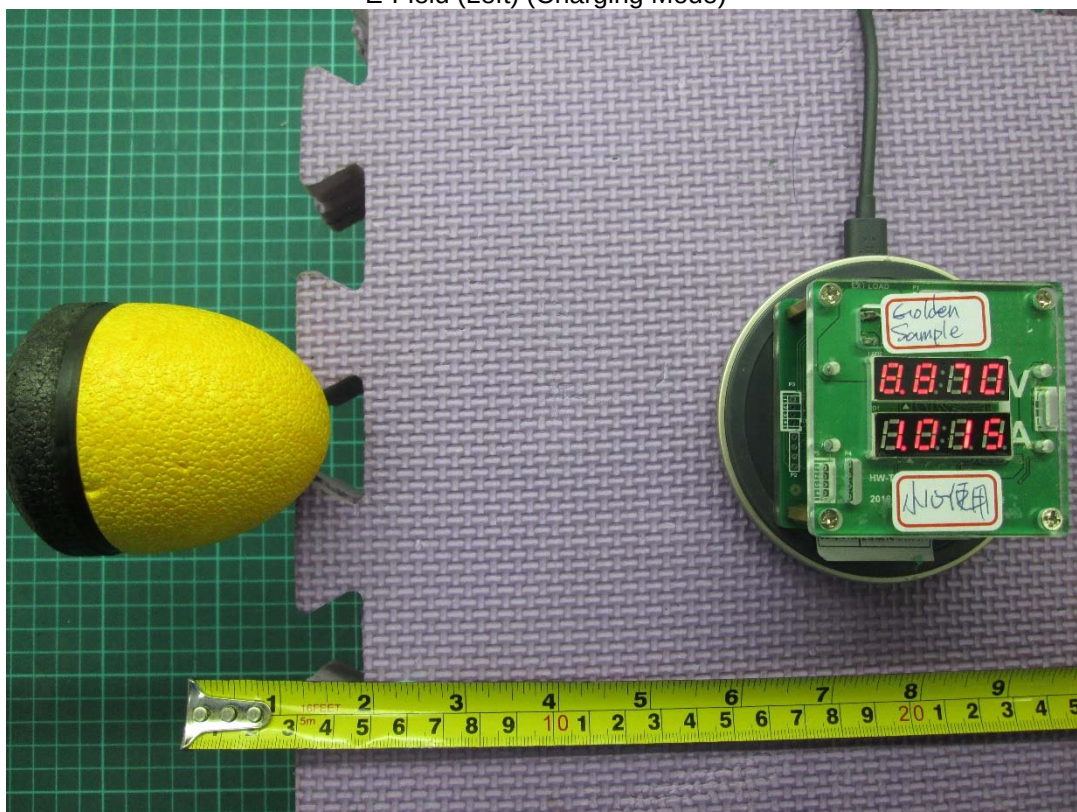


Test Mode D (EUT sample No.:006-001)

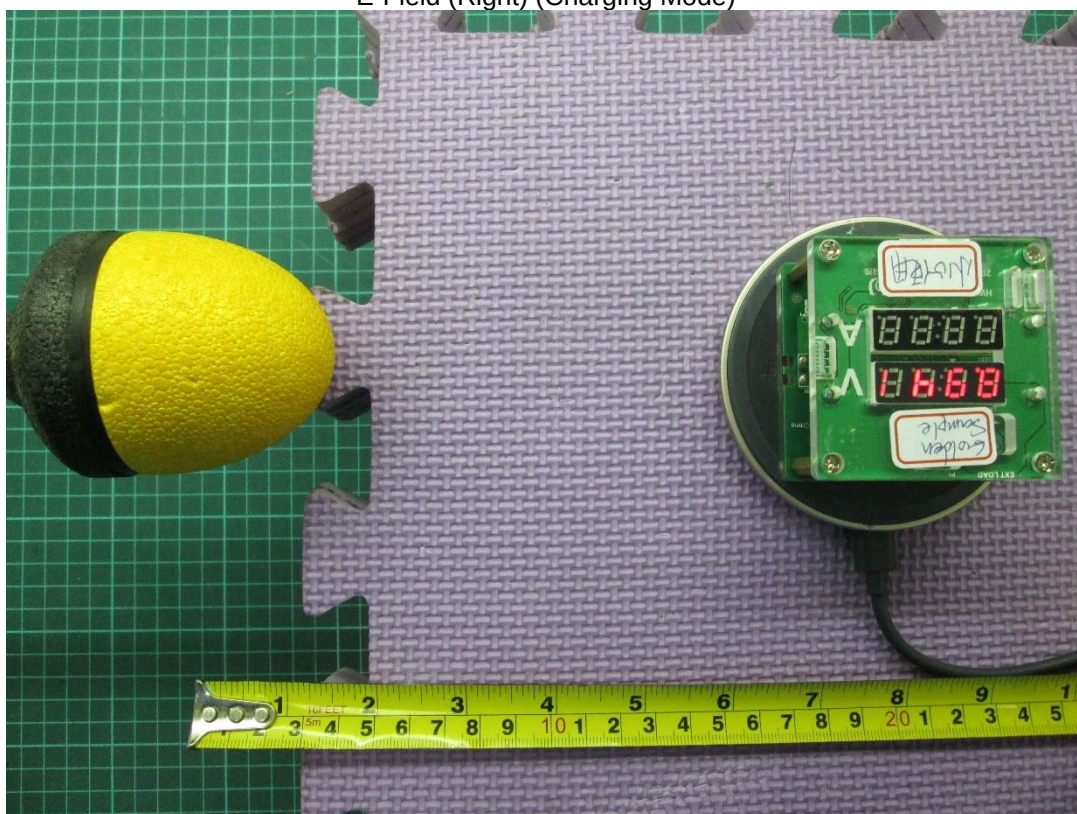


MPE

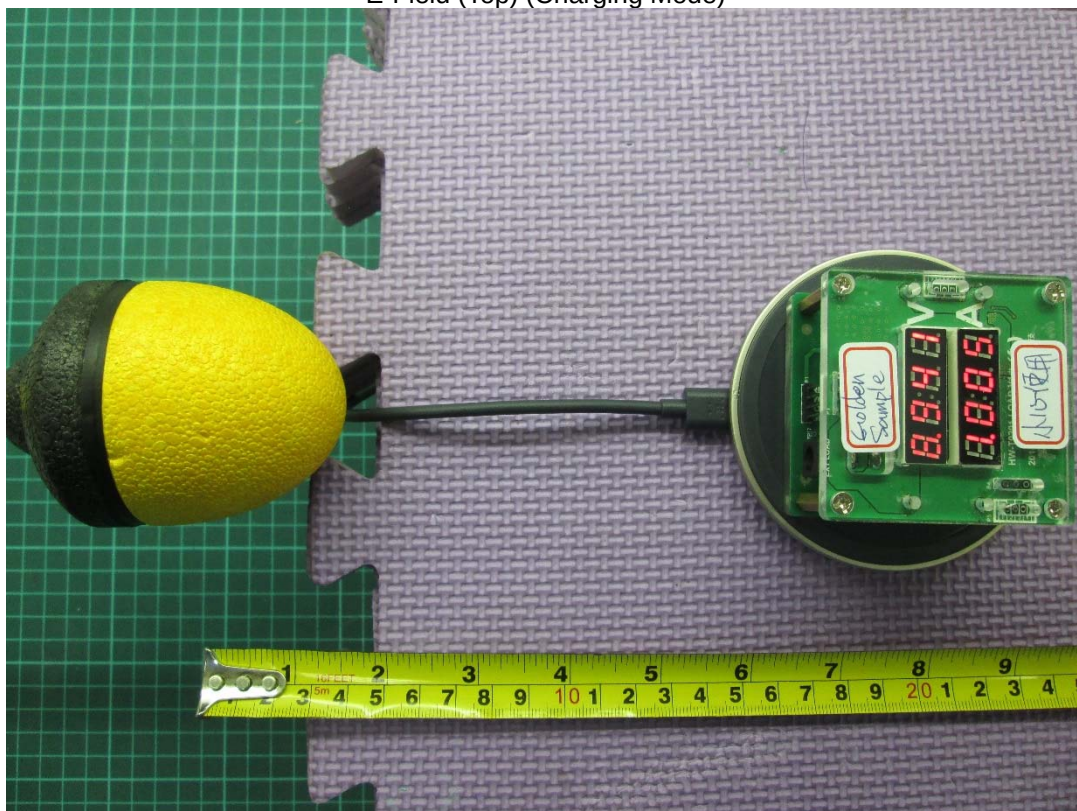
E-Field (Left) (Charging Mode)



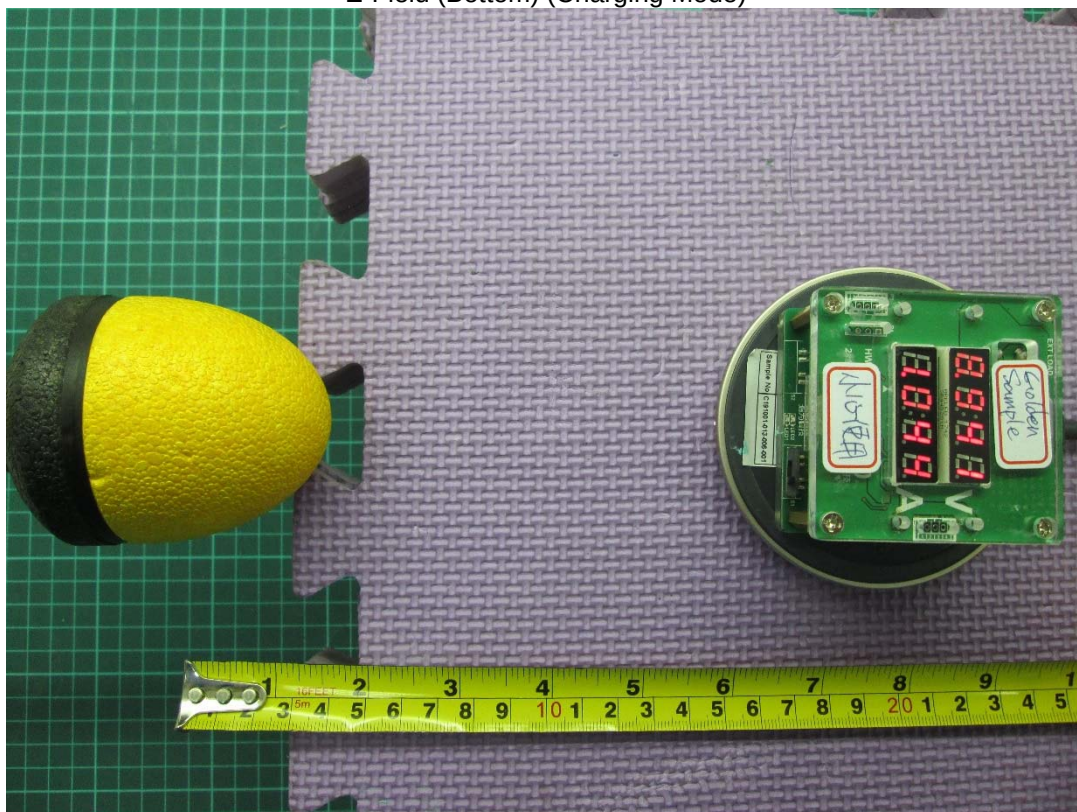
E-Field (Right) (Charging Mode)



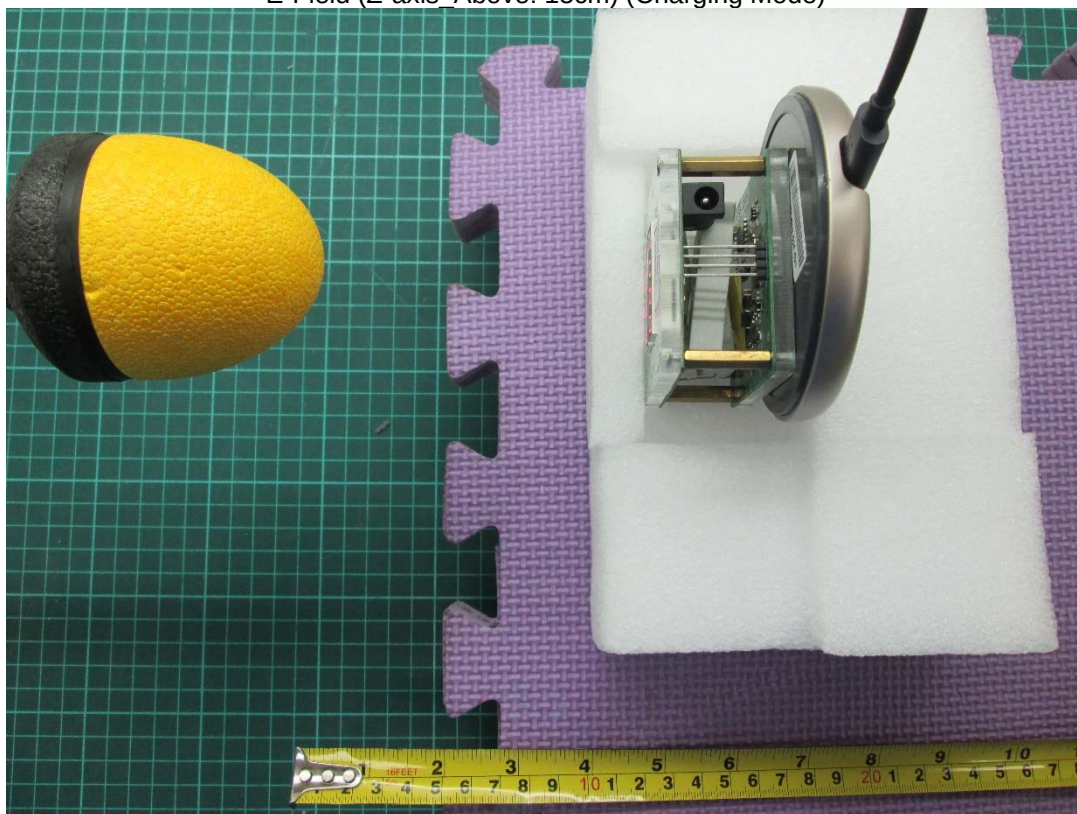
E-Field (Top) (Charging Mode)



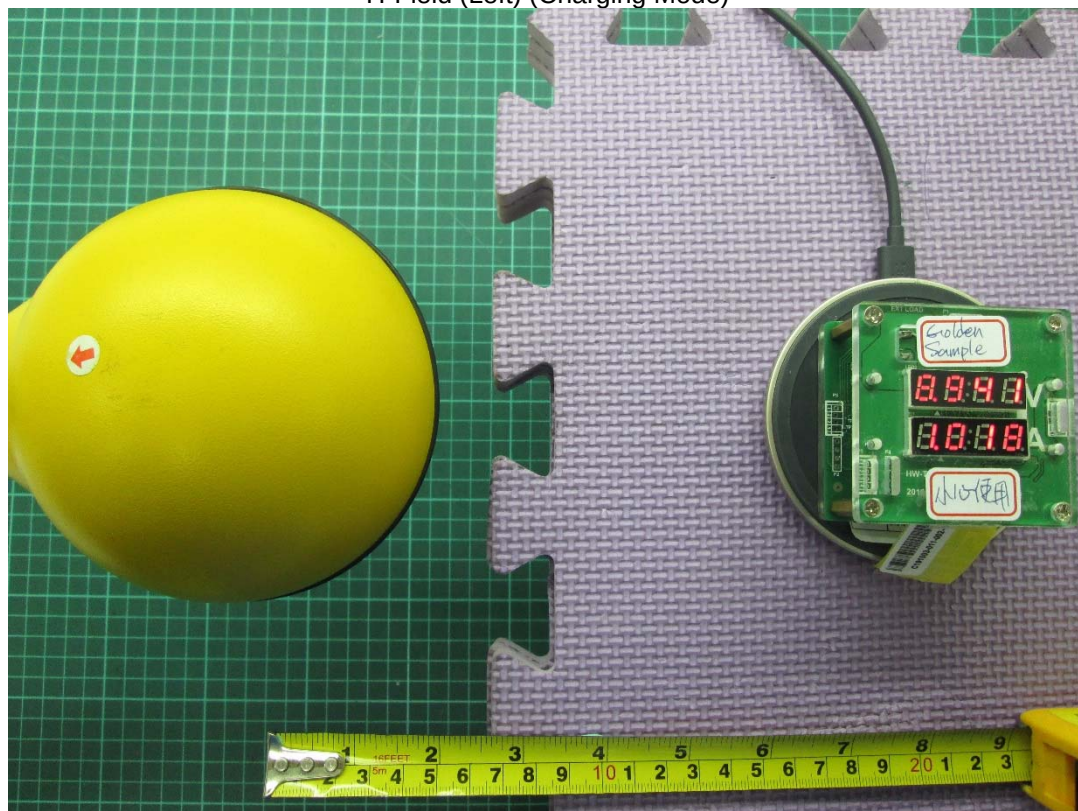
E-Field (Bottom) (Charging Mode)



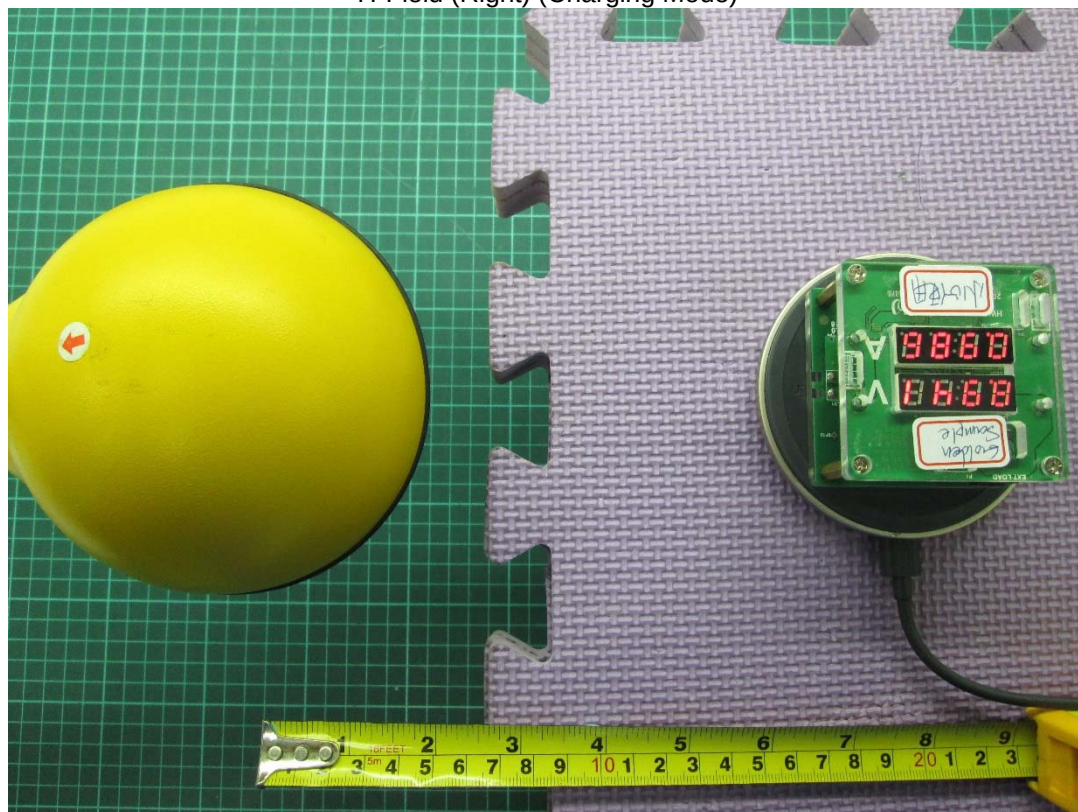
E-Field (Z-axis_Above: 15cm) (Charging Mode)



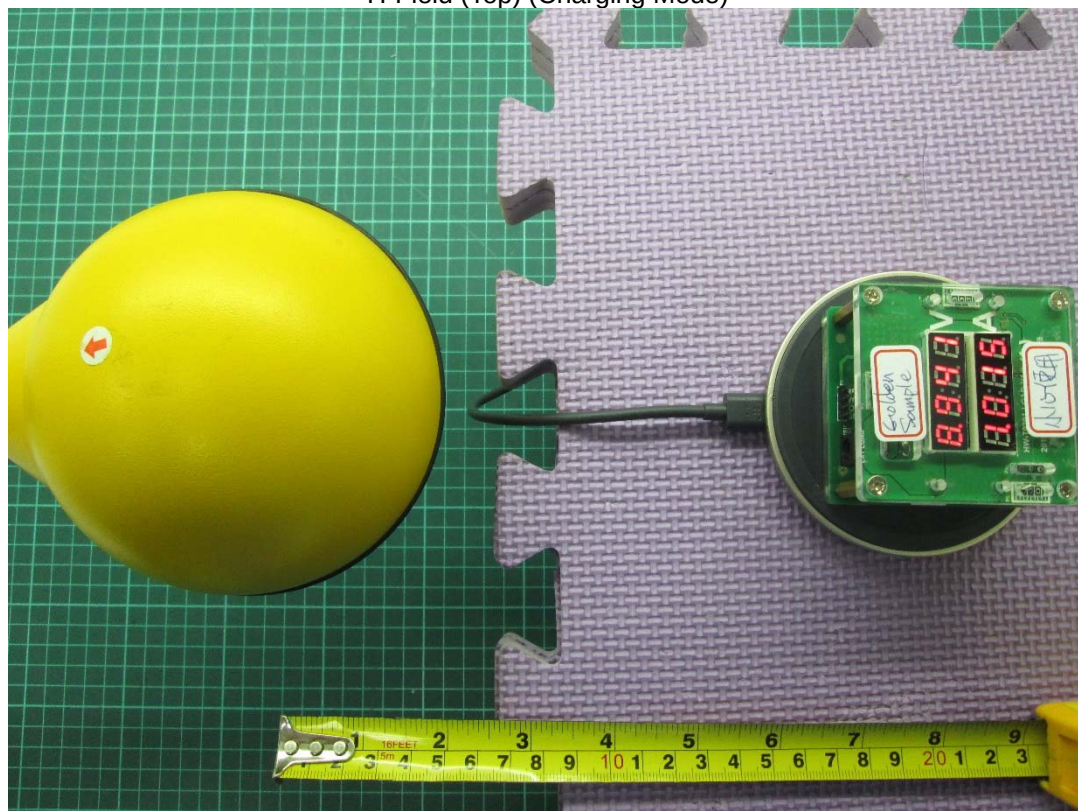
H-Field (Left) (Charging Mode)



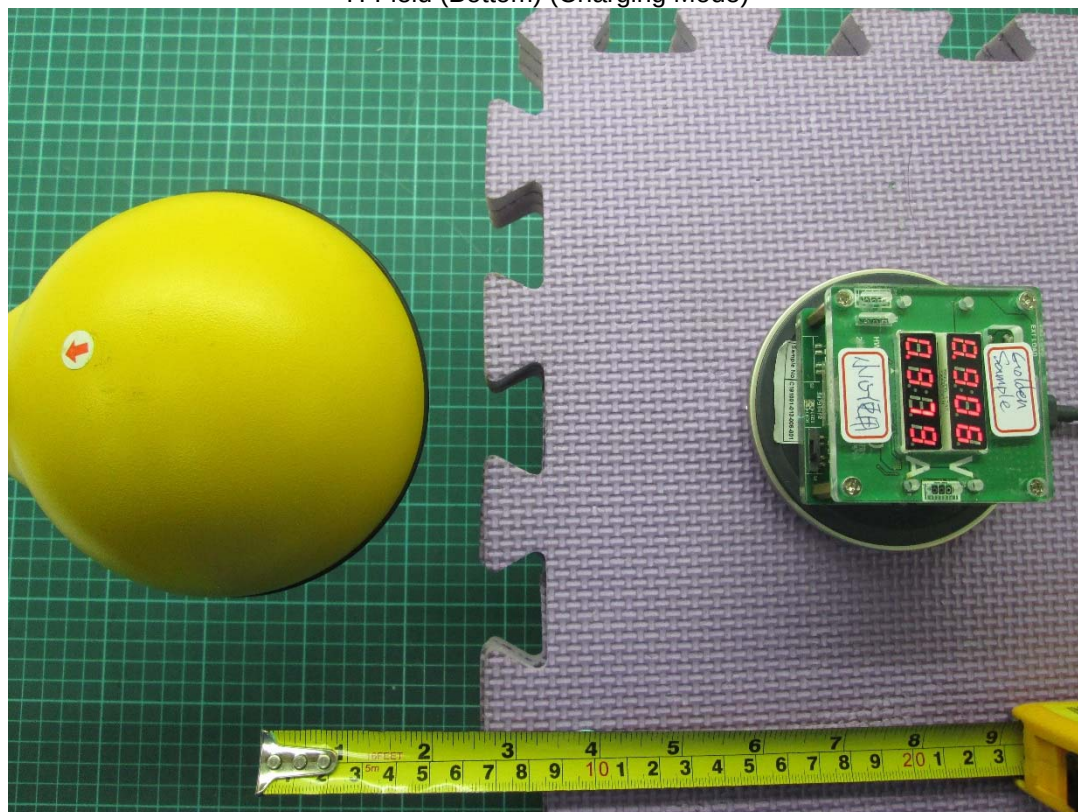
H-Field (Right) (Charging Mode)



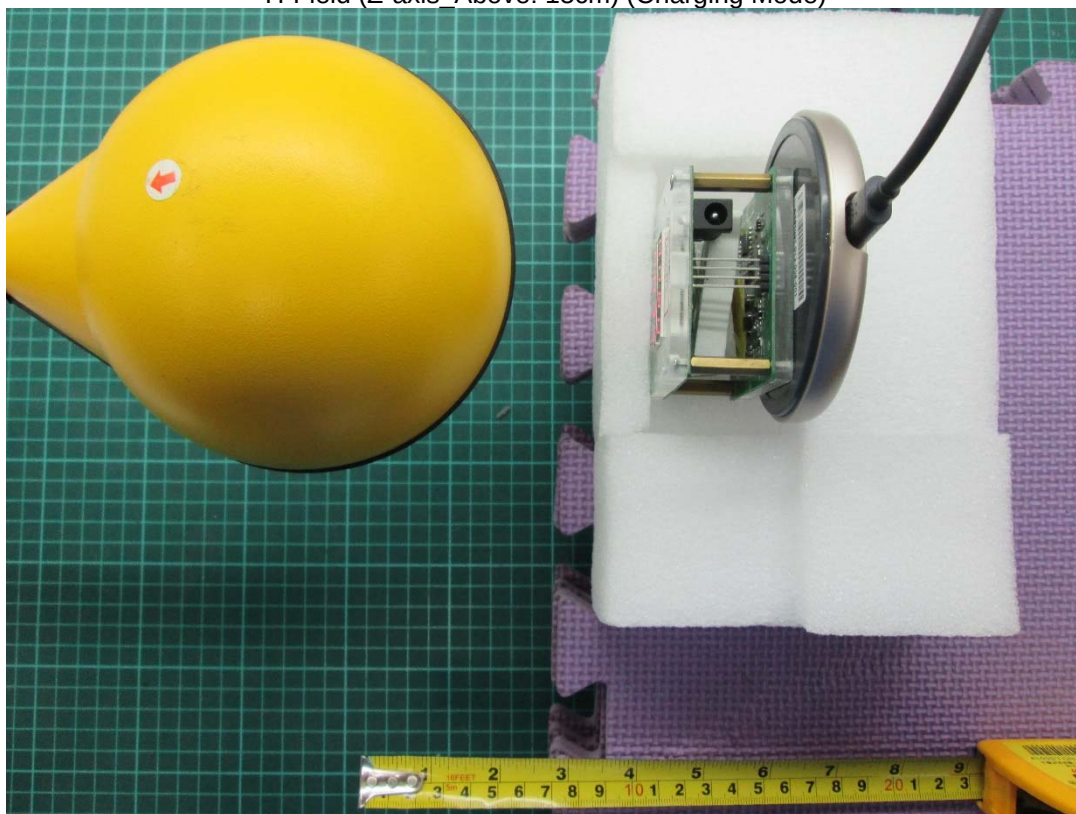
H-Field (Top) (Charging Mode)



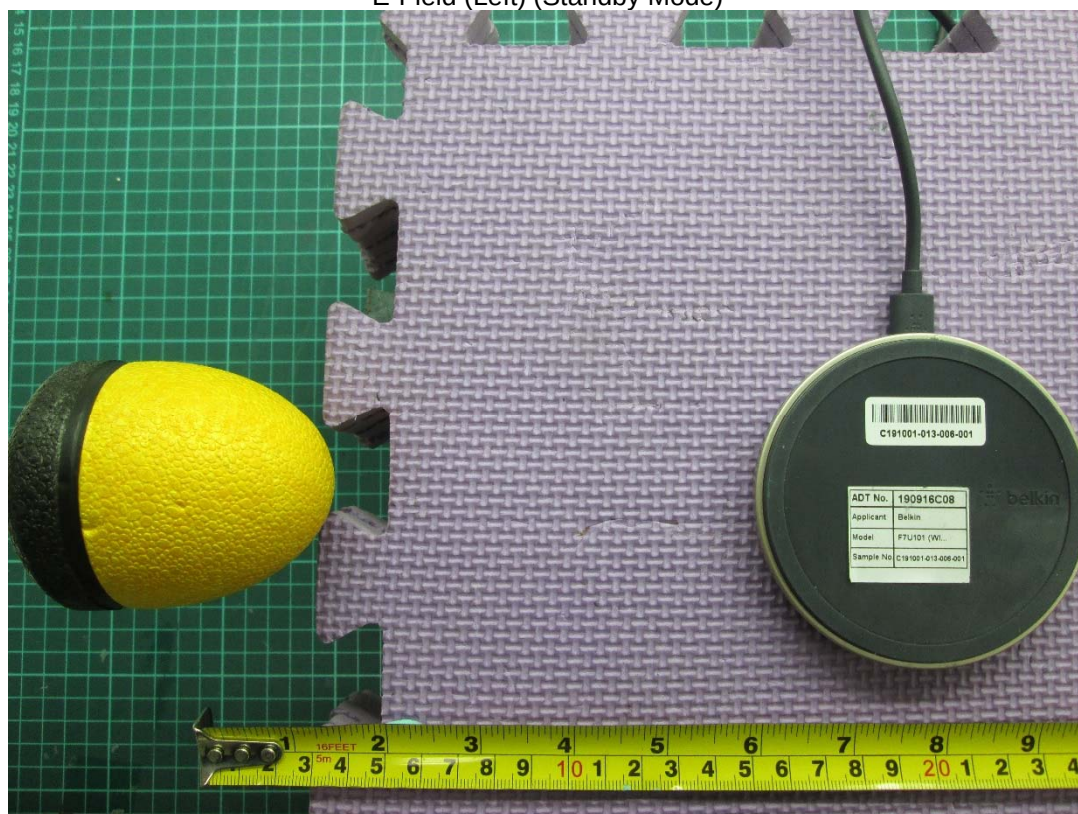
H-Field (Bottom) (Charging Mode)



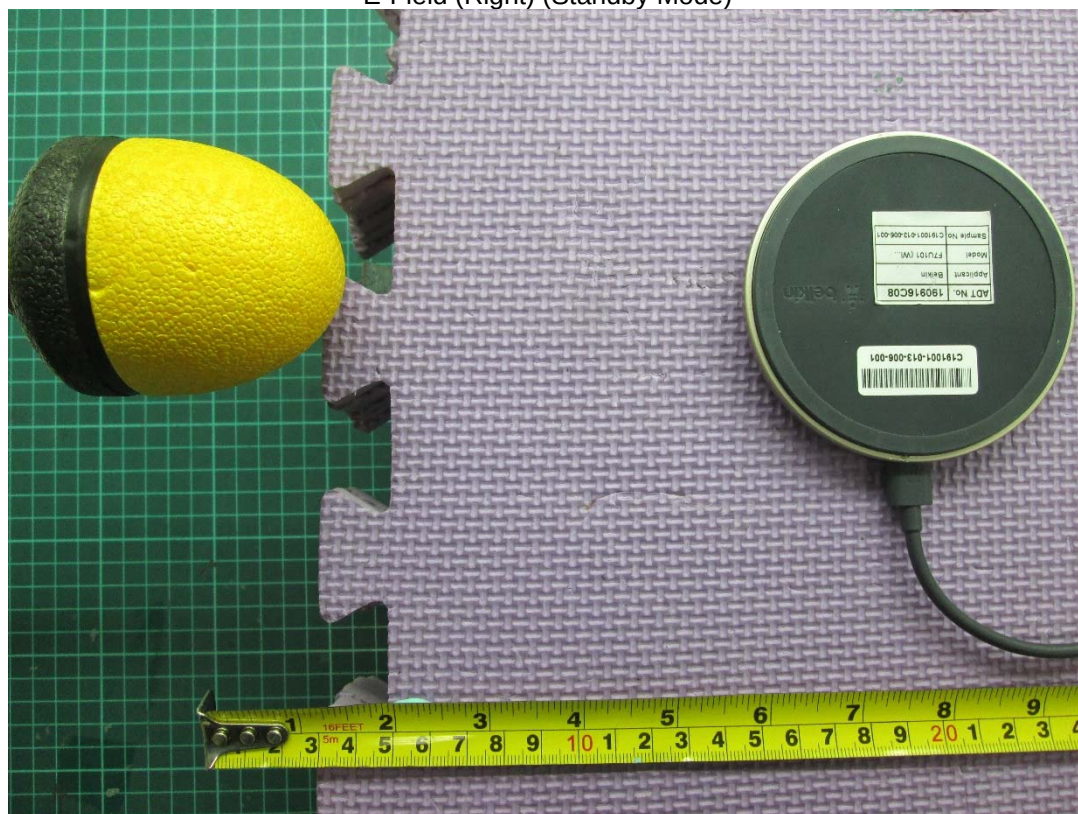
H-Field (Z-axis Above: 15cm) (Charging Mode)



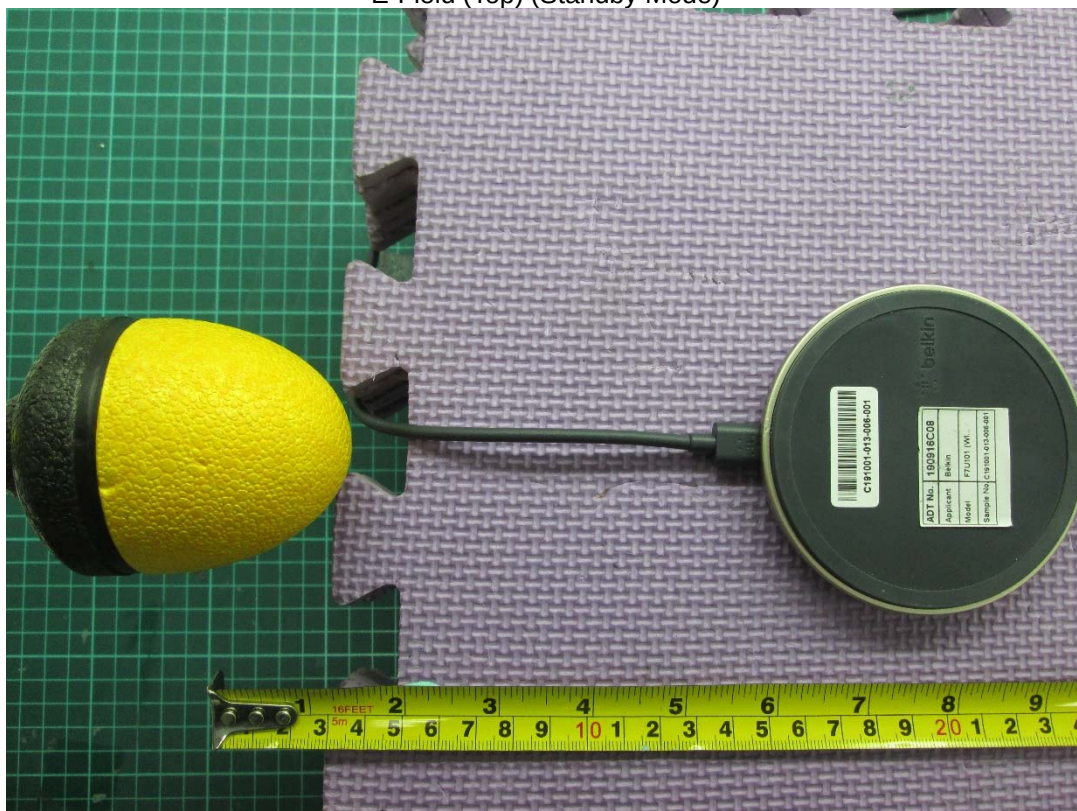
E-Field (Left) (Standby Mode)



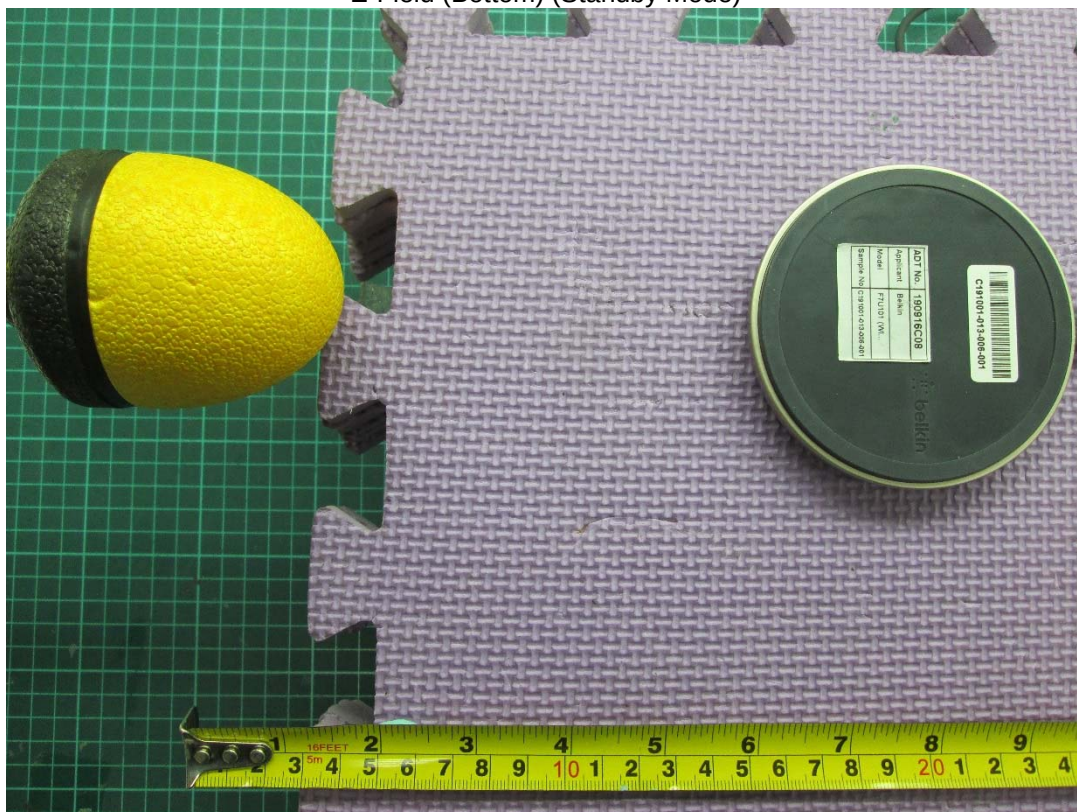
E-Field (Right) (Standby Mode)



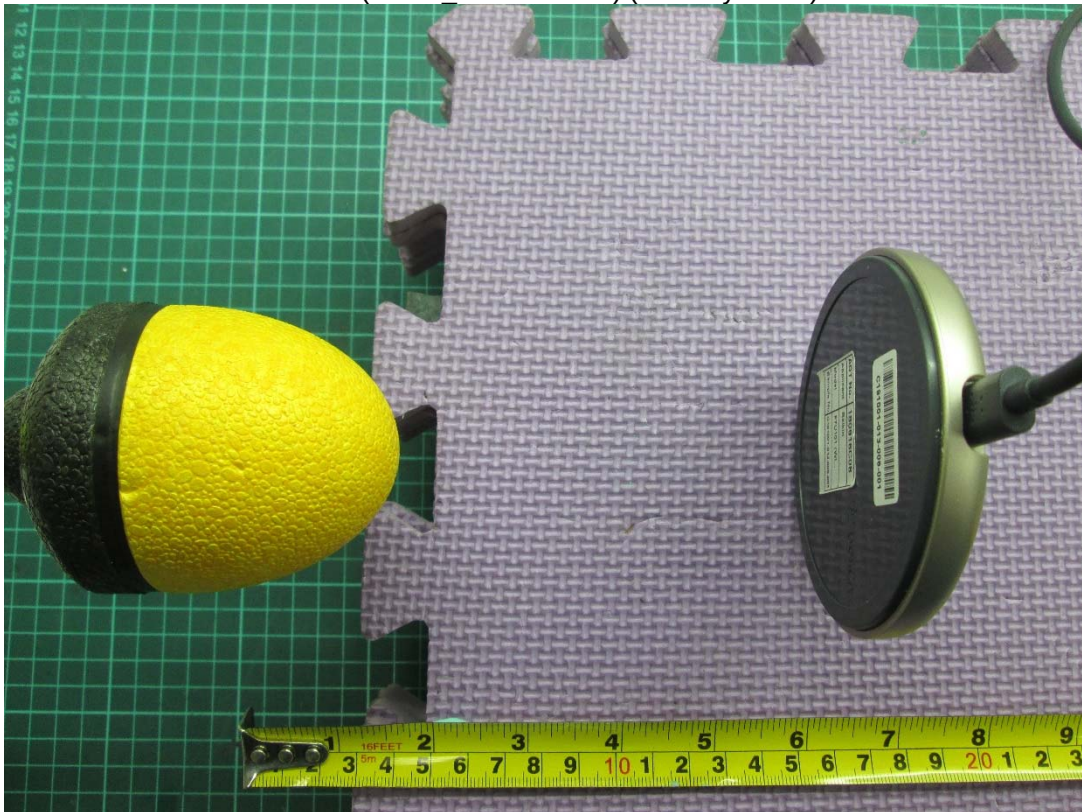
E-Field (Top) (Standby Mode)



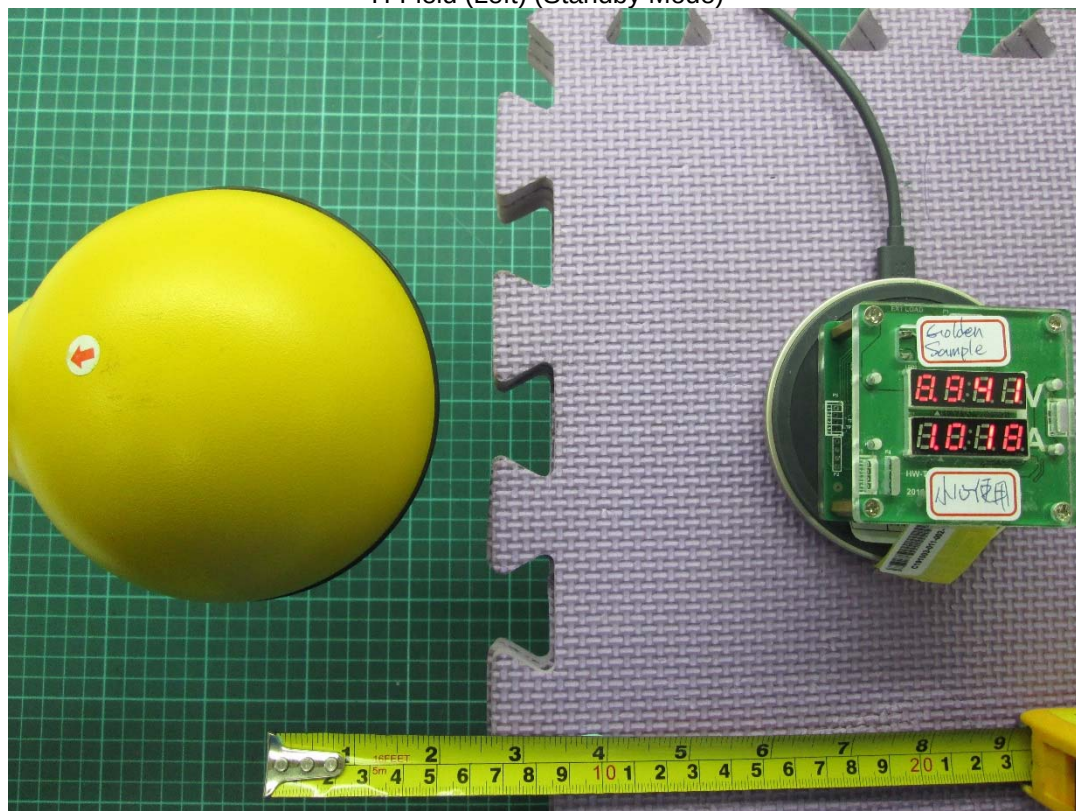
E-Field (Bottom) (Standby Mode)



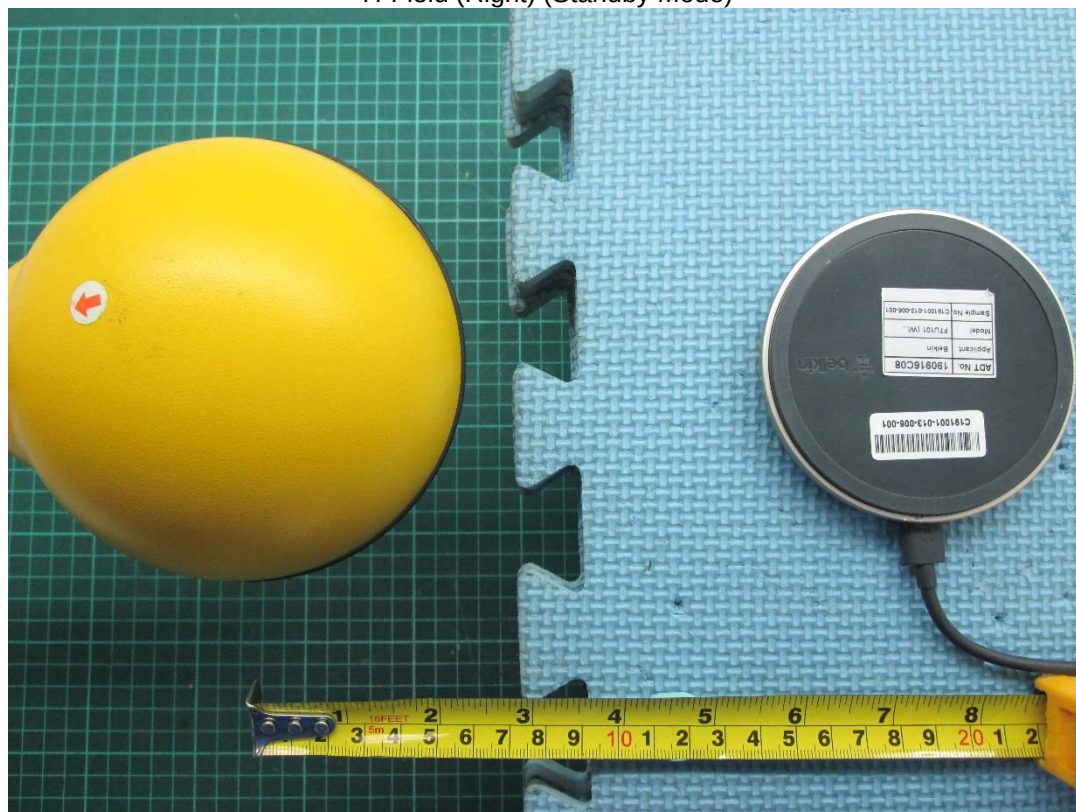
E-Field (Z-axis Above: 15cm) (Standby Mode)



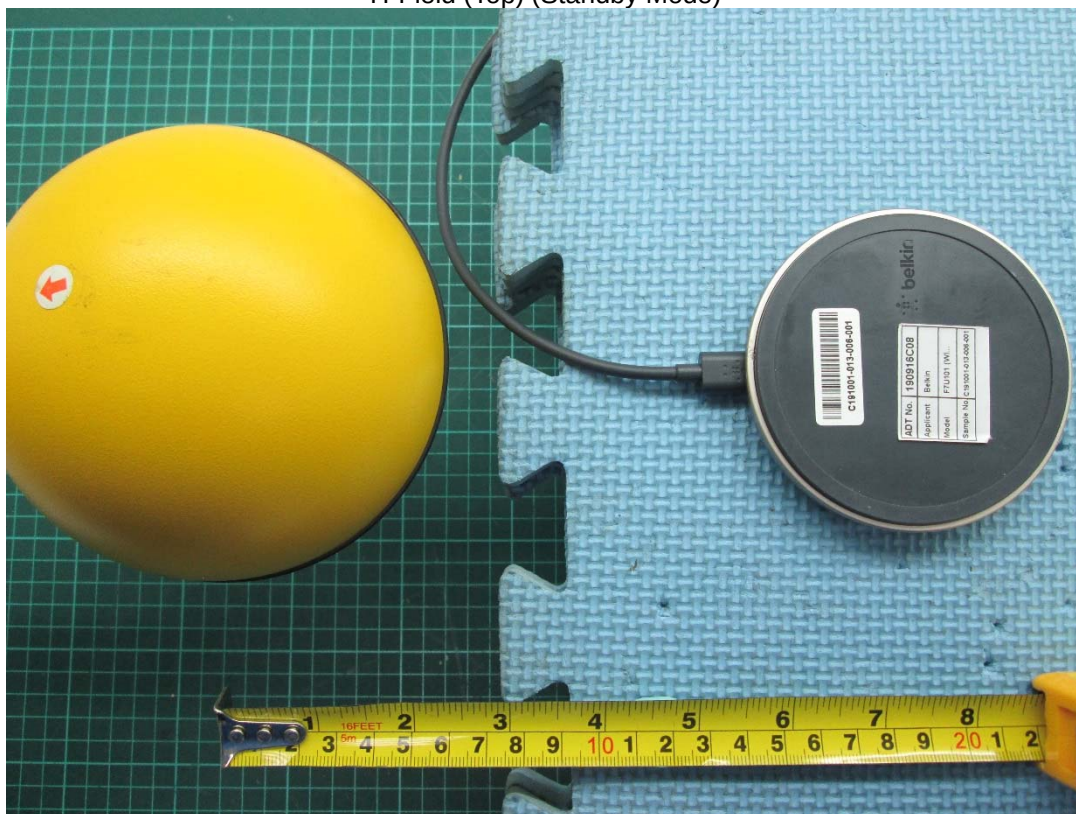
H-Field (Left) (Standby Mode)



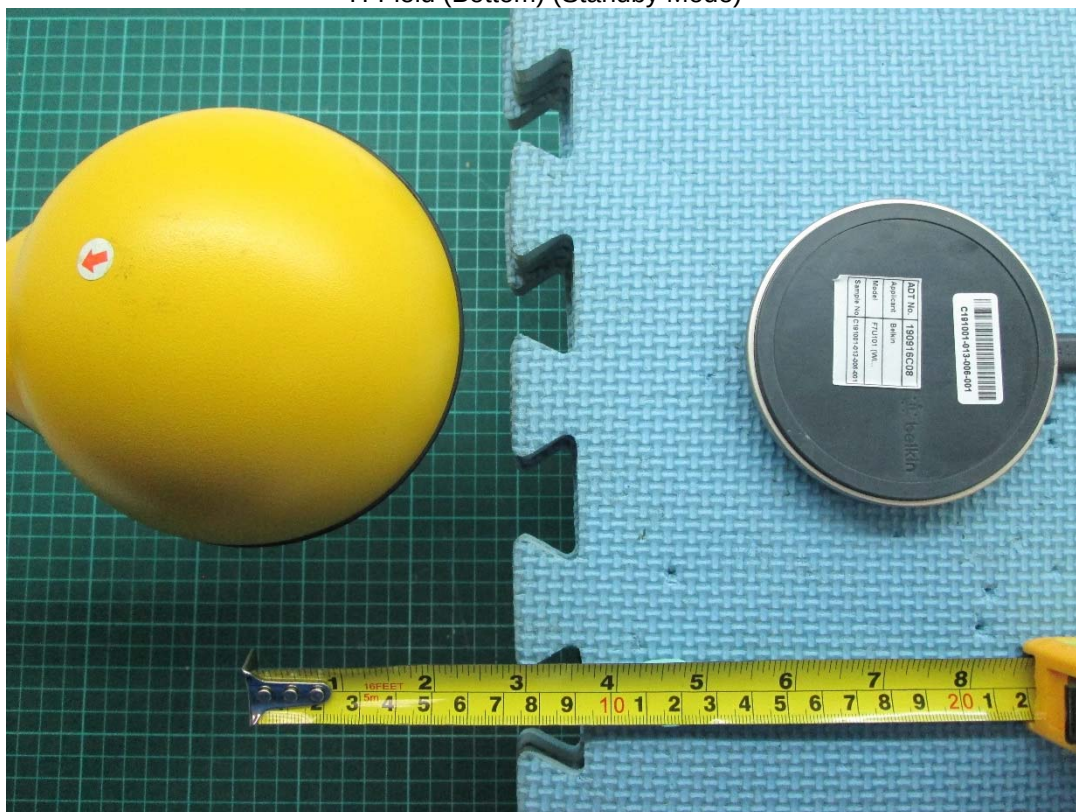
H-Field (Right) (Standby Mode)



H-Field (Top) (Standby Mode)



H-Field (Bottom) (Standby Mode)



H-Field (Z-axis_Above: 15cm) (Standby Mode)

